

**Search Notes****Application/Control No.**

10/635,916

**Examiner**

Hien X. Vo

**Applicant(s)/Patent under Reexamination**

SWAINE ET AL.

**Art Unit**

2863

**SEARCHED**

Class	Subclass	Date	Examiner
702	176	4/15/2005	VXH
	177		
	178		
	187		
711	162		
	154		
717	124		
	128		
714	45		
<u>UPDATE SEARCHED</u>			
<u>ABOVE</u>			
1/28/05 VXH			

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLus search	3/9/2005	VXH
EAST	4/13/2005	